

					+5 V
1	IP+	VCC			
2	IP+	VIOUT	7	V_{OUT}	C_{BYP} 0.1 μF
IP ACS712					
3	IP-	FILTER	6		
4	IP-	GND	5	C_F 1 nF	

ACS712

Fully Integrated, Hall Effect-Based Linear Current Sensor with 2.1 kVRMS Voltage Isolation and a Low-Resistance Current Conductor

Description (continued)

loss. The thickness of the copper conductor allows survival of the device at up to 5× overcurrent conditions. The terminals of the conductive path are electrically isolated from the sensor leads (pins 5 through 8). This allows the ACS712 current sensor to be used in applications requiring electrical isolation without the use of opto-isolators or other costly isolation techniques.

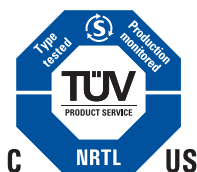
The ACS712 is provided in a small, surface mount SOIC8 package. The leadframe is plated with 100% matte tin, which is compatible with standard lead (Pb) free printed circuit board assembly processes. Internally, the device is Pb-free, except for flip-chip high-temperature Pb-based solder balls, currently exempt from RoHS. The device is fully calibrated prior to shipment from the factory.

Selection Guide

Part Number	Packing*	T _{OP} (°C)	Optimized Range, I _P (A)	Sensitivity, Sens (Typ) (mV/A)

Absolute Maximum Ratings

Characteristic	Symbol	Notes	Rating	Units

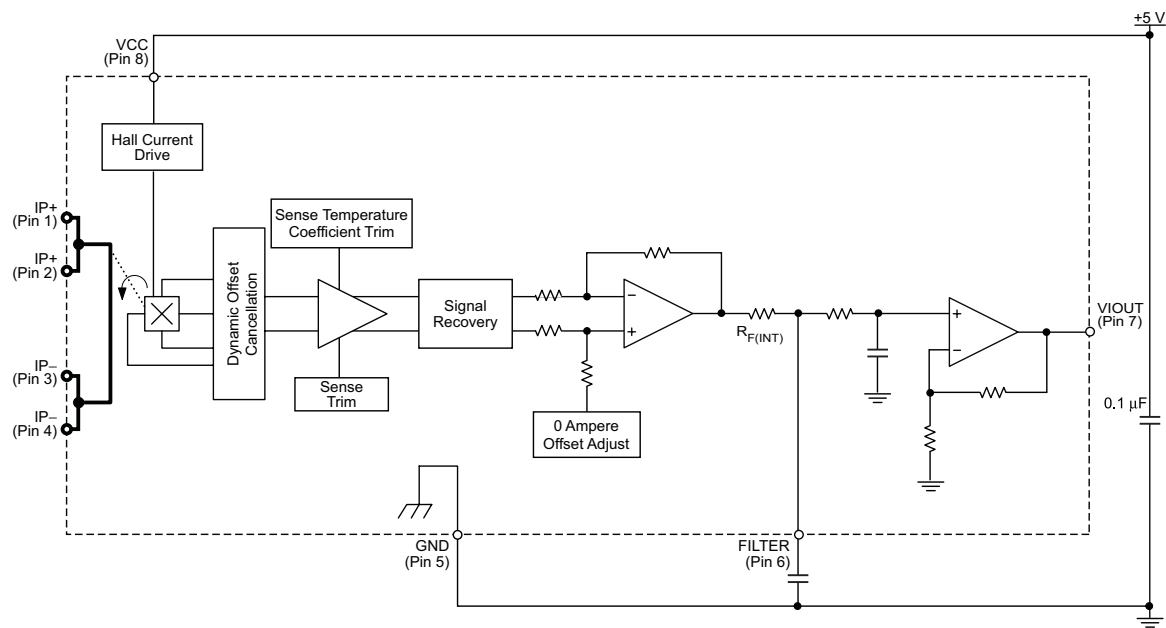


Parameter	Specification

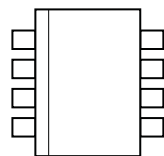
ACS712

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Functional Block Diagram



Pin-out Diagram



Terminal List Table

Number	Name	Description

ACS712

Fully Integrated, Hall Effect-Based Linear Current Sensor with
2.1 kVRMS Voltage Isolation and a Low-Resistance Current Conductor

COMMON OPERATING CHARACTERISTICS¹

Characteristic	Symbol	Test Conditions	Min.	Typ.	Max.	Units
ELECTRICAL CHARACTERISTICS						
						Ω
						Ω
						Ω
						μ
						μ
						μ
						μ
						Ω

COMMON THERMAL CHARACTERISTICS¹

	θ				
	θ				

ACS712

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x05A PERFORMANCE CHARACTERISTICS

Characteristic	Symbol	Test Conditions	Min.	Typ.	Max.	Units

x20A PERFORMANCE CHARACTERISTICS

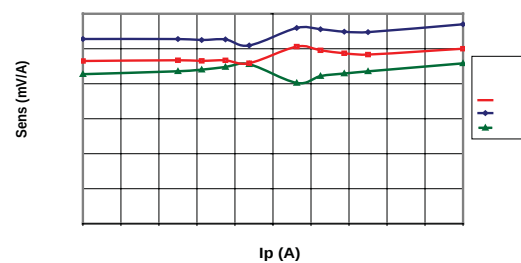
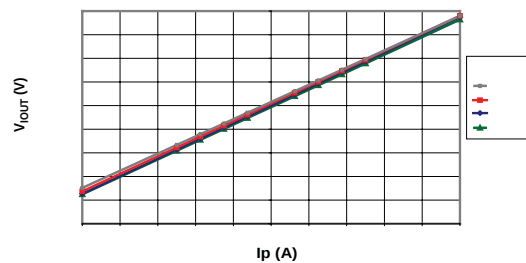
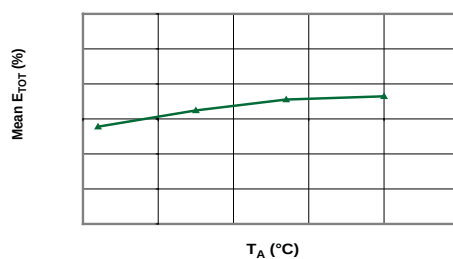
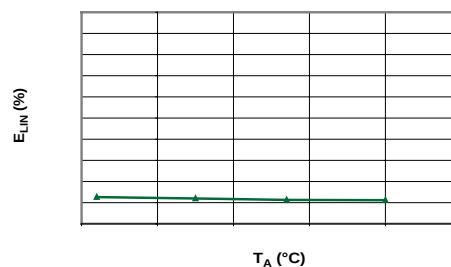
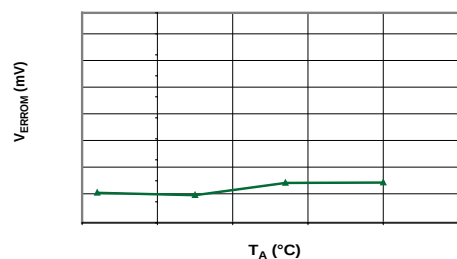
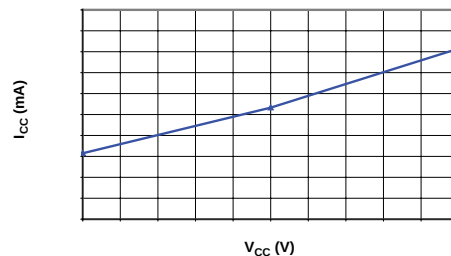
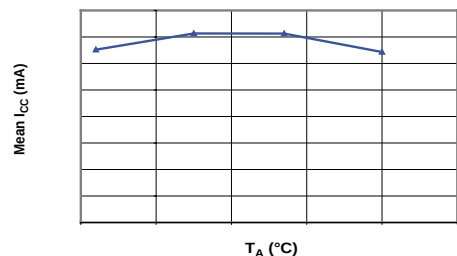
Characteristic	Symbol	Test Conditions	Min.	Typ.	Max.	Units

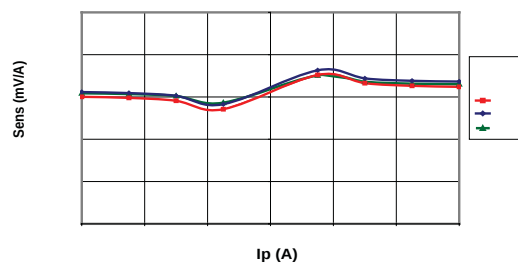
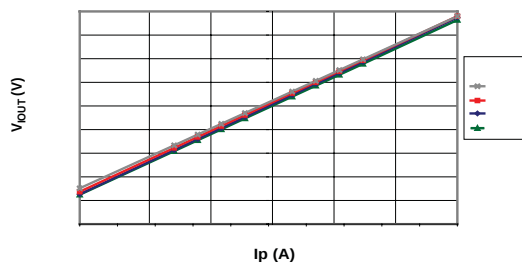
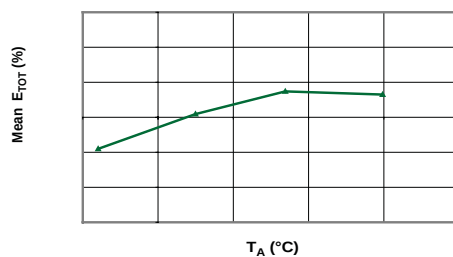
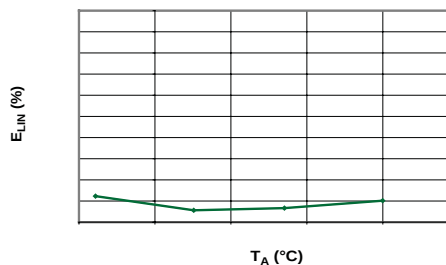
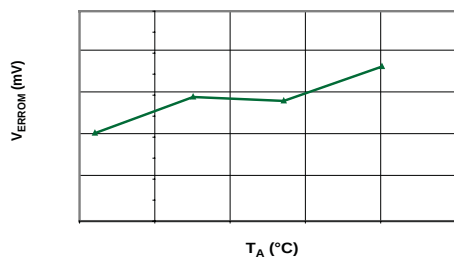
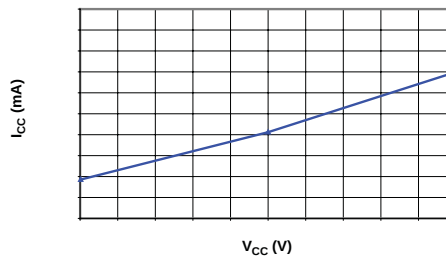
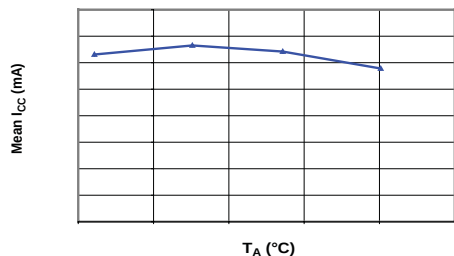
x30A PERFORMANCE CHARACTERISTICS

Characteristic	Symbol	Test Conditions	Min.	Typ.	Max.	Units

ACS712

Fully Integrated, Hall Effect-Based Linear Current Sensor with
2.1 kVRMS Voltage Isolation and a Low-Resistance Current Conductor





Definitions of Accuracy Characteristics

Sensitivity (Sens). The change in sensor output in response to a 1 A change through the primary conductor. The sensitivity is the product of the magnetic circuit sensitivity (G/A) and the linear IC amplifier gain (mV/G). The linear IC amplifier gain is programmed at the factory to optimize the sensitivity (mV/A) for the full-scale current of the device.

Noise (V_{NOISE}). The product of the linear IC amplifier gain (mV/G) and the noise floor for the Allegro Hall effect linear IC (≈ 1 G). The noise floor is derived from the thermal and shot noise observed in Hall elements. Dividing the noise (mV) by the sensitivity (mV/A) provides the smallest current that the device is able to resolve.

Linearity (E_{LIN}). The degree to which the voltage output from the sensor varies in direct proportion to the primary current through its full-scale amplitude. Nonlinearity in the output can be attributed to the saturation of the flux concentrator approaching the full-scale current. The following equation is used to derive the linearity:

$$100 \left\{ 1 - \left[\frac{\Delta \text{gain} \times \% \text{ sat} (V_{\text{IOUT_full-scale amperes}} - V_{\text{IOUT(Q)}})}{2 (V_{\text{IOUT_half-scale amperes}} - V_{\text{IOUT(Q)}})} \right] \right\}$$

where $V_{\text{IOUT_full-scale amperes}}$ = the output voltage (V) when the sensed current approximates full-scale $\pm I_p$.

Symmetry (E_{SYM}). The degree to which the absolute voltage output from the sensor varies in proportion to either a positive or negative full-scale primary current. The following formula is used to derive symmetry:

$$100 \left(\frac{V_{\text{IOUT_+ full-scale amperes}} - V_{\text{IOUT(Q)}}}{V_{\text{IOUT(Q)}} - V_{\text{IOUT_full-scale amperes}}} \right)$$

Quiescent output voltage ($V_{\text{IOUT(Q)}}$). The output of the sensor when the primary current is zero. For a unipolar supply voltage, it nominally remains at $V_{\text{CC}}/2$. Thus, $V_{\text{CC}} = 5$ V translates into $V_{\text{IOUT(Q)}} = 2.5$ V. Variation in $V_{\text{IOUT(Q)}}$ can be attributed to the resolution of the Allegro linear IC quiescent voltage trim and thermal drift.

Electrical offset voltage (V_{OE}). The deviation of the device output from its ideal quiescent value of $V_{\text{CC}}/2$ due to nonmagnetic causes. To convert this voltage to amperes, divide by the device sensitivity, Sens.

Accuracy (E_{TOT}). The accuracy represents the maximum deviation of the actual output from its ideal value. This is also known as the total output error. The accuracy is illustrated graphically in the output voltage versus current chart at right.

Accuracy is divided into four areas:

- **0 A at 25°C.** Accuracy of sensing zero current flow at 25°C, without the effects of temperature.
- **0 A over Δ temperature.** Accuracy of sensing zero current flow including temperature effects.
- **Full-scale current at 25°C.** Accuracy of sensing the full-scale current at 25°C, without the effects of temperature.
- **Full-scale current over Δ temperature.** Accuracy of sensing full-scale current flow including temperature effects.

Ratiometry. The ratiometric feature means that its 0 A output, $V_{\text{IOUT(Q)}}$, (nominally equal to $V_{\text{CC}}/2$) and sensitivity, Sens, are proportional to its supply voltage, V_{CC} . The following formula is used to derive the ratiometric change in 0 A output voltage, $\Delta V_{\text{IOUT(Q)RAT}}$ (%).

$$100 \left(\frac{V_{\text{IOUT(Q)VCC}} / V_{\text{IOUT(Q)5V}}}{V_{\text{CC}} / 5 \text{ V}} \right)$$

The ratiometric change in sensitivity, $\Delta \text{Sens}_{\text{RAT}}$ (%), is defined as:

$$100 \left(\frac{\text{Sens}_{\text{VCC}} / \text{Sens}_{5\text{V}}}{V_{\text{CC}} / 5 \text{ V}} \right)$$

ACS712

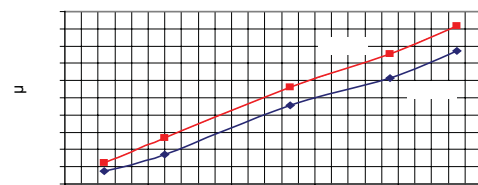
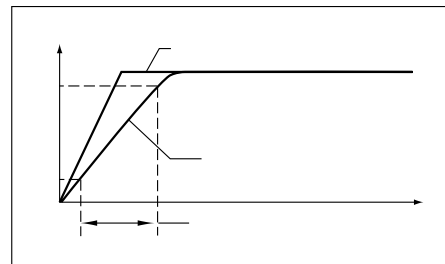
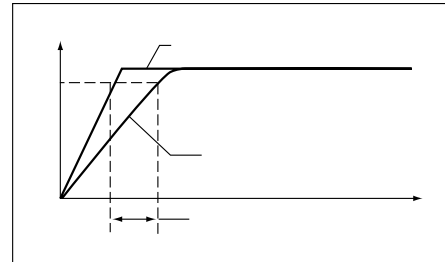
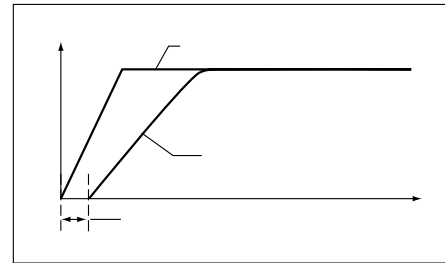
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Definitions of Dynamic Response Characteristics

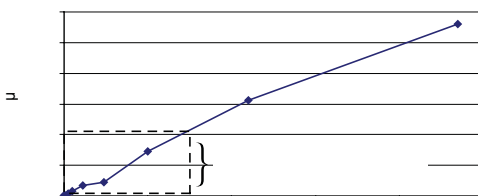
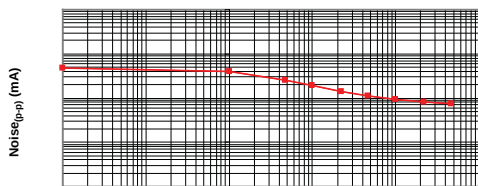
Propagation delay (t_{PROP}). The time required for the sensor output to reflect a change in the primary current signal. Propagation delay is attributed to inductive loading within the linear IC package, as well as in the inductive loop formed by the primary conductor geometry. Propagation delay can be considered as a fixed time offset and may be compensated.

Response time ($t_{RESPONSE}$). The time interval between a) when the primary current signal reaches 90% of its final value, and b) when the sensor reaches 90% of its output corresponding to the applied current.

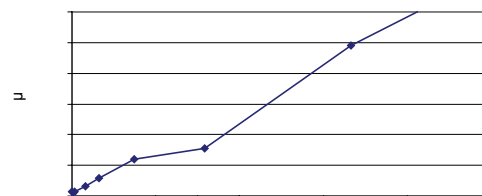
Rise time (t_r). The time interval between a) when the sensor reaches 10% of its full scale value, and b) when it reaches 90% of its full scale value. The rise time to a step response is used to derive the bandwidth of the current sensor, in which $f(-3\text{ dB}) = 0.35/t_r$. Both t_r and $t_{RESPONSE}$ are detrimentally affected by eddy current losses observed in the conductive IC ground plane.



Noise vs. Filter Cap

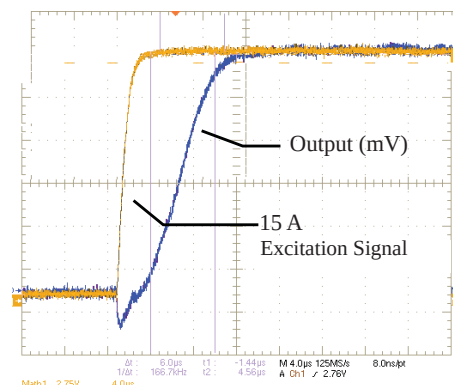


C_F (nF) t_r (μ s)



Step Response

$T_A = 25^\circ\text{C}$



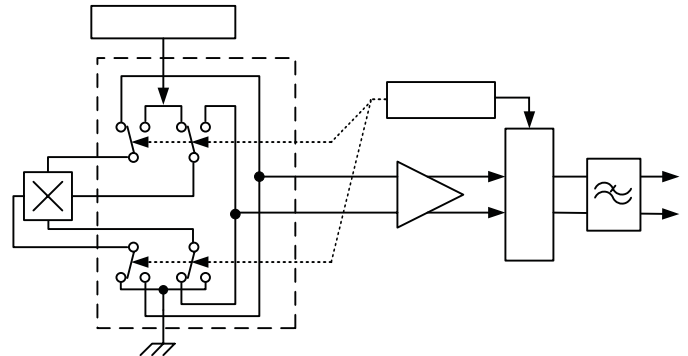
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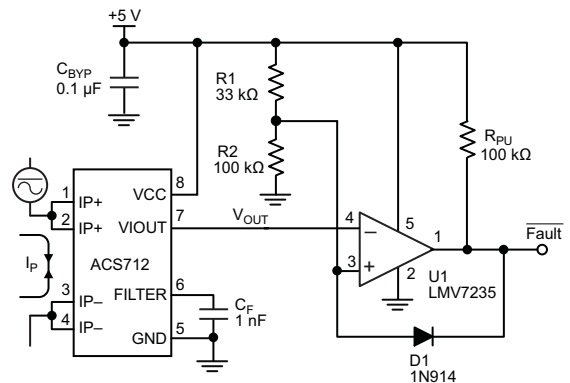
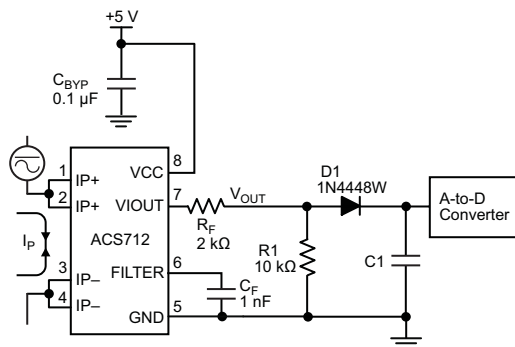
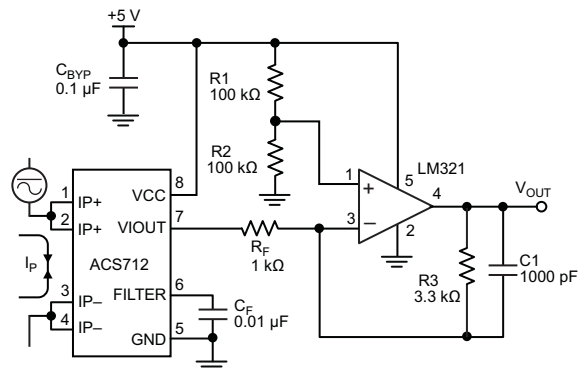
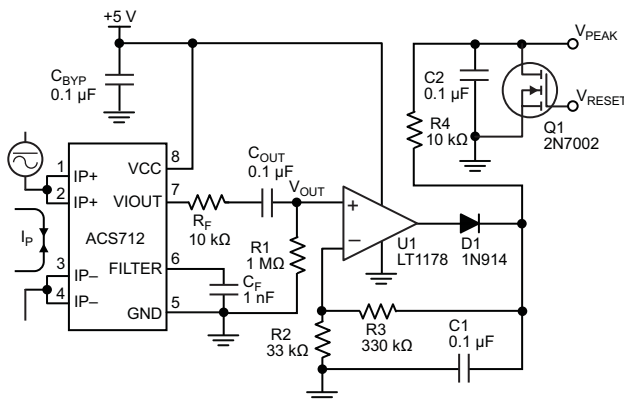
Chopper Stabilization Technique

Chopper Stabilization is an innovative circuit technique that is used to minimize the offset voltage of a Hall element and an associated on-chip amplifier. Allegro patented a Chopper Stabilization technique that nearly eliminates Hall IC output drift induced by temperature or package stress effects. This offset reduction technique is based on a signal modulation-demodulation process. Modulation is used to separate the undesired dc offset signal from the magnetically induced signal in the frequency domain. Then, using a low-pass filter, the modulated dc offset is suppressed while the magnetically induced signal passes through the filter. As a result of this chopper stabilization approach, the output voltage from the Hall IC is desensitized to the effects of temperature and mechanical stress. This technique produces devices that have an extremely stable Electrical Offset Voltage, are immune to thermal stress, and have precise recoverability after temperature cycling.

This technique is made possible through the use of a BiCMOS process that allows the use of low-offset and low-noise amplifiers in combination with high-density logic integration and sample and hold circuits.



Typical Applications



Improving Sensing System Accuracy Using the FILTER Pin

In low-frequency sensing applications, it is often advantageous to add a simple RC filter to the output of the sensor. Such a low-pass filter improves the signal-to-noise ratio, and therefore the resolution, of the sensor output signal. However, the addition of an RC filter to the output of a sensor IC can result in undesirable sensor output attenuation — even for dc signals.

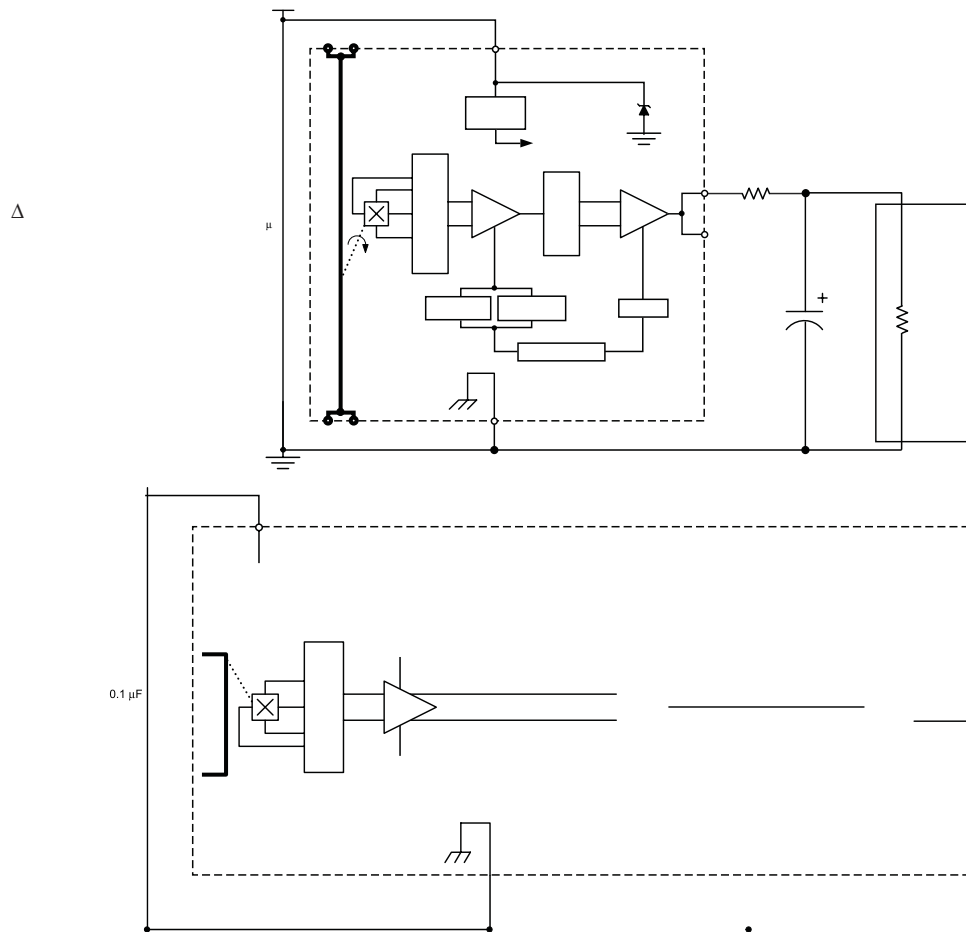
Signal attenuation, ΔV_{ATT} , is a result of the resistive divider effect between the resistance of the external filter, R_F (see Application 6), and the input impedance and resistance of the customer interface circuit, R_{INTFC} . The transfer function of this resistive divider is given by:

$$\Delta V_{ATT} = V_{IOUT} \left(\frac{R_{INTFC}}{R_F + R_{INTFC}} \right)$$

Even if R_F and R_{INTFC} are designed to match, the two individual resistance values will most likely drift by different amounts over

temperature. Therefore, signal attenuation will vary as a function of temperature. Note that, in many cases, the input impedance, R_{INTFC} , of a typical analog-to-digital converter (ADC) can be as low as 10 k Ω .

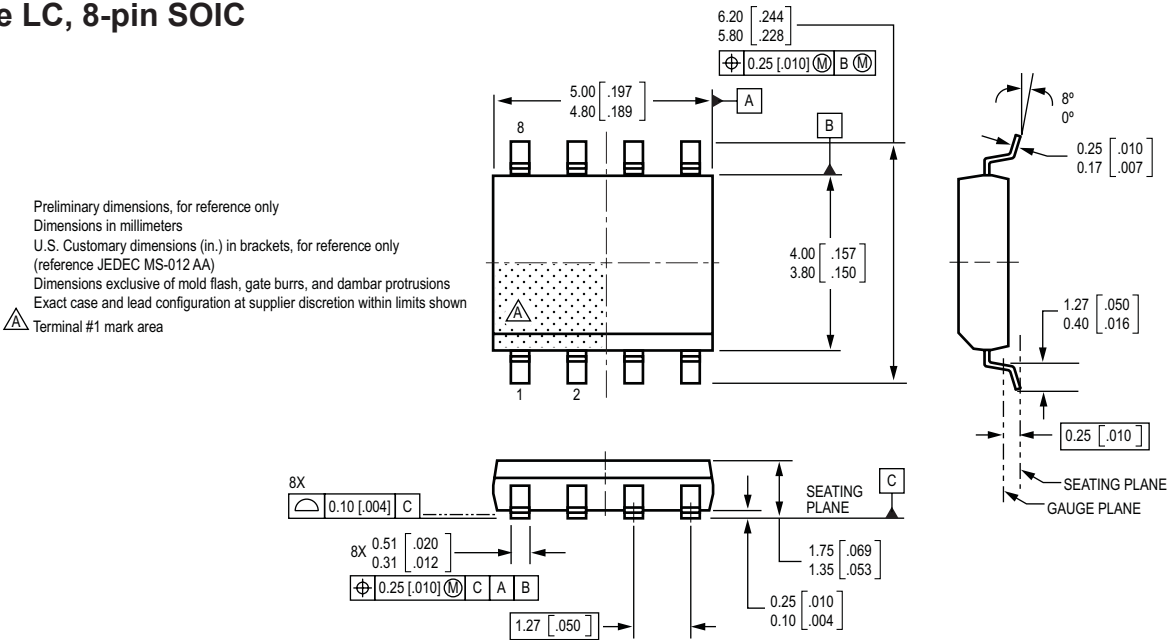
The ACS712 contains an internal resistor, a FILTER pin connection to the printed circuit board, and an internal buffer amplifier. With this circuit architecture, users can implement a simple RC filter via the addition of a capacitor, C_F (see Application 7) from the FILTER pin to ground. The buffer amplifier inside of the ACS712 (located after the internal resistor and FILTER pin connection) eliminates the attenuation caused by the resistive divider effect described in the equation for ΔV_{ATT} . Therefore, the ACS712 device is ideal for use in high-accuracy applications that cannot afford the signal attenuation associated with the use of an external RC low-pass filter.



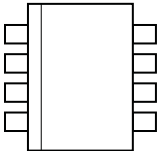
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Package LC, 8-pin SOIC



Package Branding



R PPP YYWWA	R	
	PPP	
	YY	
	WW	
	A	

R PPP L...L YYWW	R	
	PPP	
	L...L	
	YY	
	WW	

The products described herein are manufactured under one or more of the following U.S. patents: 5,045,920; 5,264,783; 5,442,283; 5,389,889; 5,581,179; 5,517,112; 5,619,137; 5,621,319; 5,650,719; 5,686,894; 5,694,038; 5,729,130; 5,917,320; and other patents pending.

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